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Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

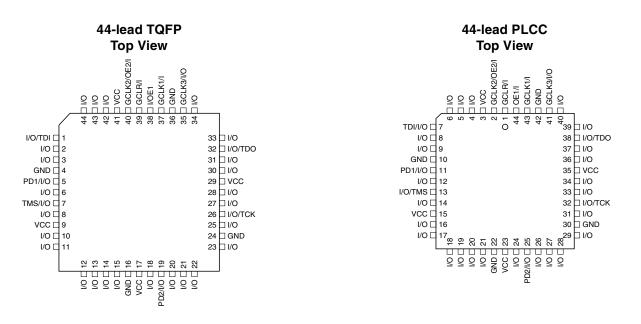
Details

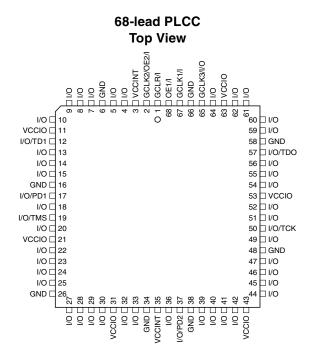
Detuns	
Product Status	Obsolete
Programmable Type	In System Programmable (min 10K program/erase cycles)
Delay Time tpd(1) Max	20 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	-
Number of Macrocells	64
Number of Gates	-
Number of I/O	64
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/atmel/atf1504asl-20ac100

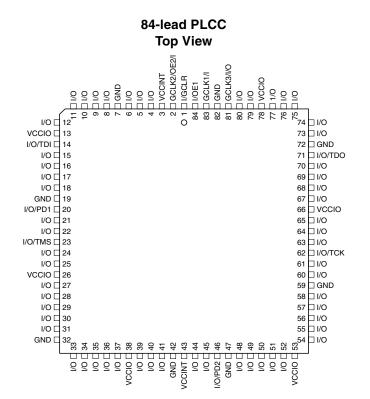
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Description

The ATF1504AS is a high-performance, high-density complex programmable logic device (CPLD) that utilizes Atmel's proven electrically-erasable memory technology. With 64 logic macrocells and up to 68 inputs, it easily integrates logic from several TTL, SSI, MSI, LSI and classic PLDs. The ATF1504AS's enhanced routing switch matrices increase usable gate count and the odds of successful pin-locked design modifications.

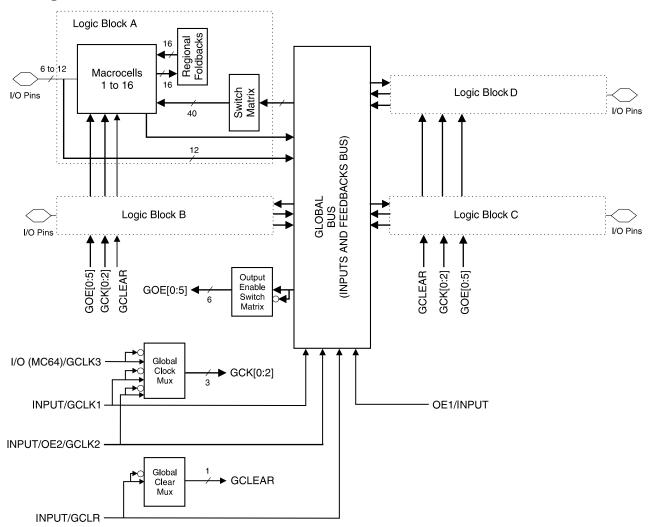
The ATF1504AS has up to 68 bi-directional I/O pins and four dedicated input pins, depending on the type of device package selected. Each dedicated pin can also serve as a global control signal, register clock, register reset or output enable. Each of these control signals can be selected for use individually within each macrocell.

Each of the 64 macrocells generates a buried feedback that goes to the global bus. Each input and I/O pin also feeds into the global bus. The switch matrix in each logic block then selects 40 individual signals from the global bus. Each macrocell also generates a foldback logic term that goes to a regional bus. Cascade logic between macrocells in the ATF1504AS allows fast, efficient generation of complex logic functions. The ATF1504AS contains four such logic chains, each capable of creating sum term logic with a fan-in of up to 40 product terms.

The ATF1504AS macrocell, shown in Figure 1, is flexible enough to support highly-complex logic functions operating at high speed. The macrocell consists of five sections: product terms and product term select multiplexer, OR/XOR/CASCADE logic, a flip-flop, output select and enable, and logic array inputs.

4 **ATF1504AS(L)**

Block Diagram



Unused product terms are automatically disabled by the compiler to decrease power consumption. A security fuse, when programmed, protects the contents of the ATF1504AS. Two bytes (16 bits) of User Signature are accessible to the user for purposes such as storing project name, part number, revision or date. The User Signature is accessible regardless of the state of the security fuse.

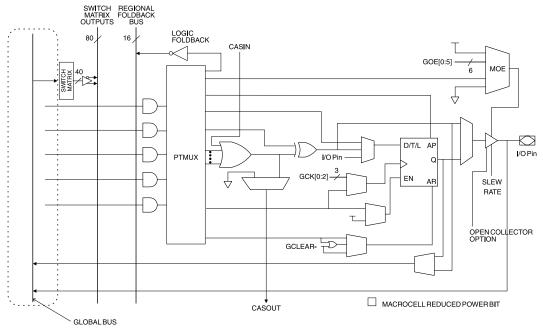
The ATF1504AS device is an in-system programmable (ISP) device. It uses the industry-standard 4-pin JTAG interface (IEEE Std. 1149.1), and is fully-compliant with JTAG's Boundary-scan Description Language (BSDL). ISP allows the device to be programmed without removing it from the printed circuit board. In addition to simplifying the manufacturing flow, ISP also allows design modifications to be made in the field via software.



Foldback Bus

Each macrocell also generates a foldback product term. This signal goes to the regional bus and is available to four macrocells. The foldback is an inverse polarity of one of the macrocell's product terms. The sixteen foldback terms in each region allow generation of high fan-in sum terms (up to sixteen product terms) with a nominal additional delay.





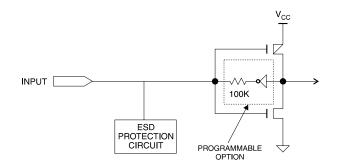




Programmable Pinkeeper Option for Inputs and I/Os

The ATF1504AS offers the option of programming all input and I/O pins so that pinkeeper circuits can be utilized. When any pin is driven high or low and then subsequently left floating, it will stay at that previous high- or low-level. This circuitry prevents unused input and I/O lines from floating to intermediate voltage levels, which causes unnecessary power consumption and system noise. The keeper circuits eliminate the need for external pull-up resistors and eliminate their DC power consumption.

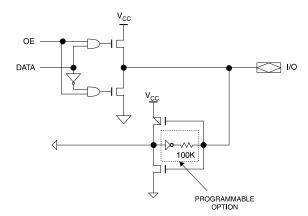
Input Diagram



Speed/Power Management

The ATF1504AS has several built-in speed and power management features. The ATF1504AS contains circuitry that automatically puts the device into a low-power standby mode when no logic transitions are occurring. This not only reduces power consumption during inactive periods, but also provides proportional power savings for most applications running at system speeds below 5 MHz. This feature may be selected as a device option.

I/O Diagram



To further reduce power, each ATF1504AS macrocell has a Reduced Power bit feature. This feature allows individual macrocells to be configured for maximum power savings. This feature may be selected as a design option.

All ATF1504AS also have an optional power-down mode. In this mode, current drops to below 10 mA. When the power-down option is selected, either PD1 or PD2 pins (or both) can be used to power-down the part. The power-down option is selected in the design source file. When enabled, the device goes into power-down when either PD1 or PD2 is high. In the power-down mode, all internal logic signals are latched and held, as are any enabled outputs.



DC and AC Operating Conditions

	Commercial	Industrial
Operating Temperature (Ambient)	0°C - 70°C	-40°C - 85°C
V _{CCINT} or V _{CCIO} (5V) Power Supply	5V ± 5%	5V ± 10%
V _{CCIO} (3.3V) Power Supply	3.0V - 3.6V	3.0V - 3.6V

DC Characteristics

Symbol	Parameter	Condition			Min	Тур	Max	Units
I _{IL}	Input or I/O Low Leakage Current	$V_{IN} = V_{CC}$	V _{IN} = V _{CC}			-2	-10	μA
I _{IH}	Input or I/O High Leakage Current					2	10	
I _{oz}	Tri-state Output Off-state Current	$V_{O} = V_{CC}$ or G	ND		-40		40	μA
			Std Modo	Com.		105		mA
L.	Power Supply Current,	V _{CC} = Max	V _{CC} = Max			130		mA
I _{CC1}	Standby	$V_{IN} = 0, V_{CC}$	"L" Mode	Com.		10		μA
						10		μΑ
I _{CC2}	Power Supply Current, Power-down Mode	$V_{CC} = Max$ $V_{IN} = 0, V_{CC}$	"PD" Mode			1	10	mA
I (2)	Current in Reduced-power	Std Power		Com		85		ma
I _{CC3} ⁽²⁾	Mode			Ind		105		
V	Supply Voltage	5.0V Device O	utout	Com.	4.75		5.25	V
V _{CCIO}	Supply voltage	5.0V Device O	ulpul	Ind.	4.5		5.5	V
V _{CCIO}	Supply Voltage	3.3V Device O	output		3.0		3.6	V
V _{IL}	Input Low Voltage				-0.3		0.8	V
V _{IH}	Input High Voltage				2.0		V _{CCIO} + 0.3	V
	Output Low Voltage (TTL)	$V_{IN} = V_{IH} \text{ or } V_{II}$	L	Com.			0.45	V
V		$V_{\rm CCIO} = MIN, I_{\rm CCIO}$	_{OL} = 12 mA	Ind.				
V _{OL}		$V_{IN} = V_{IH} \text{ or } V_{II}$	L	Com.			.2	V
	Output Low Voltage (CMOS)	$V_{\rm CC} = MIN, I_{\rm OL}$		Ind.			.2	V
V _{OH}	Output High Voltage (TTL)	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{CCIO} = MIN, I_{OH} = -4.0 \text{ mA}$			2.4			V

Notes: 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec. 2. When macrocell reduced-power feature is enabled.

Pin Capacitance

	Тур	Max	Units	Conditions
C _{IN}	8	10	pF	V _{IN} = 0V; f = 1.0 MHz
C _{I/O}	8	10	pF	$V_{OUT} = 0V; f = 1.0 \text{ MHz}$

Note: Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested. The OGI pin (high-voltage pin during programming) has a maximum capacitance of 12 pF.

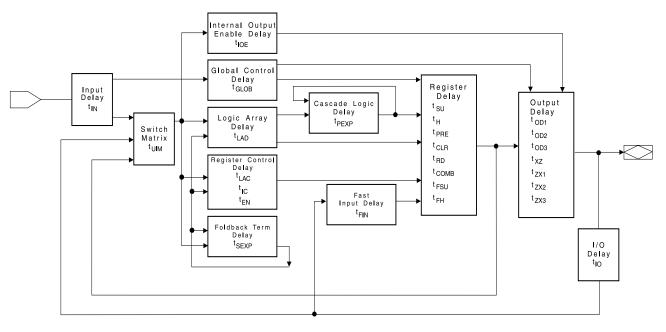


AC Characteristics (Continued)

		-7	7	-	10	-	15	-2	20	-25		
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Min	Max	Min	Мах	Units
f _{MAX}	Maximum Clock Frequency	166.7		125		100		83.3		60		MHz
t _{IN}	Input Pad and Buffer Delay		0.5		0.5		2		2		2	ns
t _{IO}	I/O Input Pad and Buffer Delay		0.5		0.5		2		2		2	ns
t _{FIN}	Fast Input Delay		1		1		2		2		2	ns
t _{SEXP}	Foldback Term Delay		4		5		8		10		12	ns
t _{PEXP}	Cascade Logic Delay		0.8		0.8		1		1		1.2	ns
t _{LAD}	Logic Array Delay		3		5		6		7		8	ns
t _{LAC}	Logic Control Delay		3		5		6		7		8	ns
t _{IOE}	Internal Output Enable Delay		2		2		3		3		4	ns
t _{OD1}	Output Buffer and Pad Delay (Slow slew rate = OFF; $V_{CCIO} = 5V; C_L = 35 pF$)		2		1.5		4		5		6	ns
t _{OD2}	Output Buffer and Pad Delay (Slow slew rate = OFF; $V_{CCIO} = 3.3V$; $C_L = 35 \text{ pF}$)		2.5		2.0		5		6		7	ns
t _{OD3}	Output Buffer and Pad Delay (Slow slew rate = ON; $V_{CCIO} = 5V$ or 3.3V; $C_L = 35 \text{ pF}$)		5		5.5		8		10		10	ns

Note: See ordering information for valid part numbers.

Timing Model







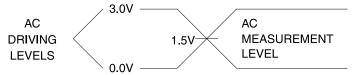
AC Characteristics (Continued)

		-	7	-	10	-	15	-:	20	-:	25	
Symbol	Parameter	Min	Max	Units								
t _{ZX1}	Output Buffer Enable Delay (Slow slew rate = OFF; $V_{CCIO} = 5.0V; C_L = 35 pF$)		4.0		5.0		7		9		10	ns
t _{ZX2}	Output Buffer Enable Delay (Slow slew rate = OFF; $V_{CCIO} = 3.3V; C_L = 35 pF$)		4.5		5.5		7		9		10	ns
t _{ZX3}	Output Buffer Enable Delay (Slow slew rate = ON; $V_{CCIO} = 5.0V/3.3V; C_L = 35 pF$)		9		9		10		11		12	ns
t _{xz}	Output Buffer Disable Delay $(C_L = 5 \text{ pF})$		4		5		6		7		8	ns
t _{SU}	Register Setup Time	3		3		4		5		6		ns
t _H	Register Hold Time	2		3		4		5		6		ns
t _{FSU}	Register Setup Time of Fast Input	3		3		2		2		3		ns
t _{FH}	Register Hold Time of Fast Input	0.5		0.5		2		2		2.5		ns
t _{RD}	Register Delay		1		2		1		2		2	ns
t _{COMB}	Combinatorial Delay		1		2		1		2		2	ns
t _{IC}	Array Clock Delay		3		5		6		7		8	ns
t _{EN}	Register Enable Time		3		5		6		7		8	ns
t _{GLOB}	Global Control Delay		1		1		1		1		1	ns
t _{PRE}	Register Preset Time		2		3		4		5		6	ns
t _{CLR}	Register Clear Time		2		3		4		5		6	ns
t _{UIM}	Switch Matrix Delay		1		1		2		2		2	ns
t _{RPA}	Reduced-power Adder ⁽²⁾		10		11		13		14		15	ns

Notes: 1. See ordering information for valid part numbers.

 The t_{RPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{TIC}, t_{ACL}, and t_{SEXP} parameters for macrocells running in the reducedpower mode.

Input Test Waveforms and Measurement Levels

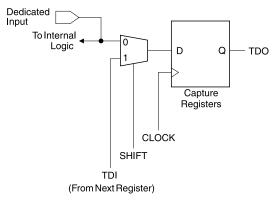


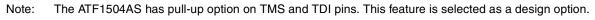
 $t_{\rm R}$, $t_{\rm F}$ = 1.5 ns typical

MEI
R

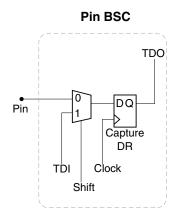
JTAG-BST/ISP Overview	The JTAG boundary-scan testing is controlled by the Test Access Port (TAP) controller in the ATF1504AS. The boundary-scan technique involves the inclusion of a shift-regis- ter stage (contained in a boundary-scan cell) adjacent to each component so that signals at component boundaries can be controlled and observed using scan testing principles. Each input pin and I/O pin has its own boundary-scan cell (BSC) in order to support boundary scan testing. The ATF1504AS does not currently include a Test Reset (TRST) input pin because the TAP controller is automatically reset at power-up. The five JTAG modes supported include: SAMPLE/PRELOAD, EXTEST, BYPASS, IDCODE and HIGHZ. The ATF1504AS's ISP can be fully described using JTAG's BSDL as described in IEEE Standard 1149.1b. This allows ATF1504AS programming to be described and implemented using any one of the third-party development tools support- ing this standard.
	The ATF1504AS has the option of using four JTAG-standard I/O pins for boundary-scan testing (BST) and in-system programming (ISP) purposes. The ATF1504AS is programmable through the four JTAG pins using the IEEE standard JTAG programming protocol established by IEEE Standard 1149.1 using 5V TTL-level programming signals from the ISP interface for in-system programming. The JTAG feature is a programmable option. If JTAG (BST or ISP) is not needed, then the four JTAG control pins are available as I/O pins.
JTAG Boundary-scan Cell (BSC) Testing	The ATF1504AS contains up to 68 I/O pins and four input pins, depending on the device type and package type selected. Each input pin and I/O pin has its own boundary-scan cell (BSC) in order to support boundary-scan testing as described in detail by IEEE Standard 1149.1. A typical BSC consists of three capture registers or scan registers and up to two update registers. There are two types of BSCs, one for input or I/O pin, and one for the macrocells. The BSCs in the device are chained together through the capture registers. Input to the capture register chain is fed in from the TDI pin while the output is directed to the TDO pin. Capture registers are used to capture active device data signals, to shift data in and out of the device and to load data into the update registers. Control signals are generated internally by the JTAG TAP controller. The BSC configuration for the input and I/O pins and macrocells are shown below.

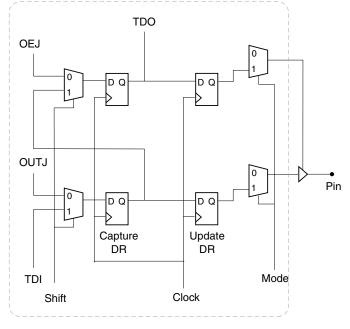
BSC Configuration for Input and I/O Pins (Except JTAG TAP Pins)





BSC Configuration for Macrocell





Macrocell BSC





ATF1504AS Dedicated Pinouts

	44-lead	44-lead	68-lead	84-lead	100-lead	100-lead
Dedicated Pin	TQFP	J-lead	J-lead	J-lead	PQFP	TQFP
INPUT/OE2/GCLK2	40	2	2	2	92	90
INPUT/GCLR	39	1	1	1	91	89
INPUT/OE1	38	44	68	84	90	88
INPUT/GCLK1	37	43	67	83	89	87
I/O /GCLK3	35	41	65	81	87	85
I/O/PD (1,2)	5, 19	11, 25	17, 37	20, 46	14, 44	12, 42
I/O/TDI (JTAG)	1	7	12	14	6	4
I/O/TMS (JTAG)	7	13	19	23	17	15
I/O/TCK (JTAG)	26	32	50	62	64	62
I/O/TDO (JTAG)	32	38	57	71	75	73
GND	4, 16, 24, 36	10, 22, 30, 42	6, 16, 26, 34, 38, 48, 58, 66	7, 19, 32, 42, 47, 59, 72, 82	13, 28, 40, 45, 61, 76, 88, 97	11, 26, 38, 43, 59, 74, 86, 95
V _{CCINT}	9, 17, 29, 41	3, 15, 23, 35	3, 35	3, 43	41, 93	39, 91
V _{CCIO}	_	_	11, 21, 31, 43, 53, 63	13, 26, 38, 53, 66, 78	5, 20, 36, 53, 68, 84	3, 18, 34, 51, 66, 82
N/C	_	_	_	_	1, 2, 7, 9, 24, 26, 29, 30, 51, 52, 55, 57, 72, 74, 79, 80	1, 2, 5, 7, 22, 24, 27, 28, 49, 50, 53, 55, 70, 72, 77, 78
# of Signal Pins	36	36	52	68	68	68
# User I/O Pins	32	32	48	64	64	64
OE (1, 2)	Global	OE Pins				
GCLR	Global	Clear Pin				
GCLK (1, 2, 3)	Global	Clock Pins				
PD (1, 2)	Power of	down pins				

TDI, TMS, TCK, TDO JTAG pins used for boundary-scan testing or in-system programming

GND Ground Pins

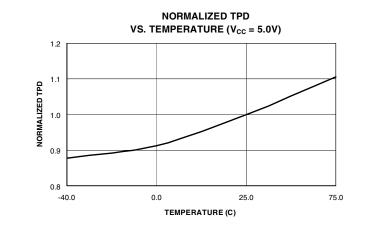
V_{CCINT} VCC pins for the device (+5V - Internal)

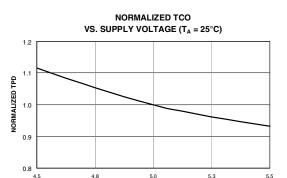
V_{CCIO} VCC pins for output drivers (for I/O pins) (+5V or 3.3V - I/Os)

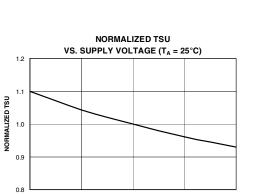
ATF1504AS I/O Pinouts

мс	PLC	44- lead PLCC	44- lead TQFP	68- lead PLCC	84- lead PLCC	100- lead PQFP	100- lead TQFP	МС	PLC	44- lead PLCC	44- lead TQFP	68- lead PLCC	84- lead PLCC	100- lead PQFP	100- lead TQFP
1	А	12	6	18	22	16	14	33	С	24	18	36	44	42	40
2	Α	-	_	-	21	15	13	34	С	_	-	_	45	43	41
3	A/ PD1	11	5	17	20	14	12	35	C/ PD2	25	19	37	46	44	42
4	Α	9	3	15	18	12	10	36	С	26	20	39	48	46	44
5	Α	8	2	14	17	11	9	37	С	27	21	40	49	47	45
6	Α	-	-	13	16	10	8	38	С	_	_	41	50	48	46
7	Α	-	-	_	15	8	6	39	С	_	_	-	51	49	47
8/ TDI	А	7	1	12	14	6	4	40	С	28	22	42	52	50	48
9	Α	-	-	10	12	4	100	41	С	29	23	44	54	54	52
10	Α	-	_	_	11	3	99	42	С	_	_	-	55	56	54
11	Α	6	44	9	10	100	98	43	С	_	_	45	56	58	56
12	Α	-	-	8	9	99	97	44	С	_	-	46	57	59	57
13	Α	-	-	7	8	98	96	45	С	_	_	47	58	60	58
14	А	5	43	5	6	96	94	46	С	31	25	49	60	62	60
15	А	-	-	-	5	95	93	47	С	-	-	-	61	63	61
16	А	4	42	4	4	94	92	48/ TCK	С	32	26	50	62	64	62
17	В	21	15	33	41	39	37	49	D	33	27	51	63	65	63
18	В	-	-	_	40	38	36	50	D	_	-	-	64	66	64
19	В	20	14	32	39	37	35	51	D	34	28	52	65	67	65
20	В	19	13	30	37	35	33	52	D	36	30	54	67	69	67
21	В	18	12	29	36	34	32	53	D	37	31	55	68	70	68
22	В	-	-	28	35	33	31	54	D	_	-	56	69	71	69
23	В	1	_	_	34	32	30	55	D	_	_	1	70	73	71
24	В	17	11	27	33	31	29	56/ TDO	D	38	32	57	71	75	73
25	В	16	10	25	31	27	25	57	D	39	33	59	73	77	75
26	В	-	-	-	30	25	23	58	D	-	-	_	74	78	76
27	В	-	-	24	29	23	21	59	D	-	-	60	75	81	79
28	В	-	-	23	28	22	20	60	D	-	-	61	76	82	80
29	В	-	-	22	27	21	19	61	D	-	-	62	77	83	81
30	В	14	8	20	25	19	17	62	D	40	34	64	79	85	83
31	В	I	-	-	24	18	16	63	D	-	-	Ι	80	86	84
32/ TMS	В	13	7	19	23	17	15	64	D/ GCLK3	41	35	65	81	87	85









5.0

SUPPLY VOLTAGE (V)

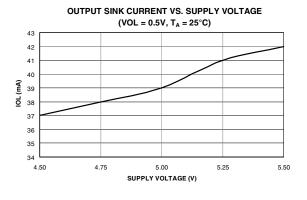
5.3

5.5

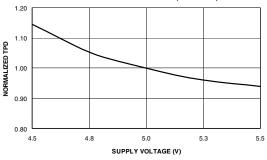
4.5

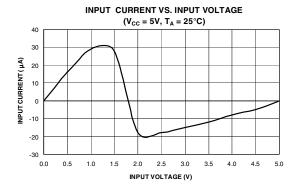
4.8

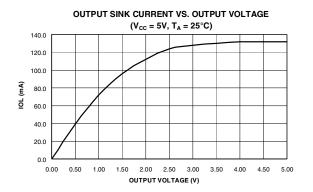
SUPPLY VOLTAGE (V)





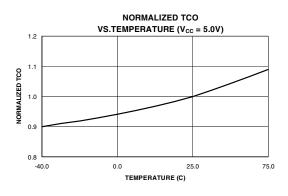


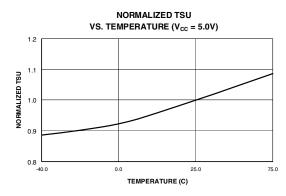














t _{PD} (ns)	t _{CO1} (ns)	f _{MAX} (MHz)	Ordering Code	Package	Operation Range
20	12	83.3	ATF1504ASL-20 AC44	44A	Commercial
			ATF1504ASL-20 JC44	44J	(0°C to 70°C)
			ATF1504ASL-20 JC68	68J	
			ATF1504ASL-20 JC84	84J	
			ATF1504ASL-20 QC100	100Q1	
			ATF1504ASL-20 AC100	100A	
25	15	70	ATF1504ASL-25 AI44	44A	Industrial
			ATF1504ASL-25 JI84	44J	(-40°C to +85°C)
			ATF1504ASL-25 JI68	68J	
			ATF1504ASL-25 JI84	84J	
			ATF1504ASL-25 QI100	100Q1	
			ATF1504ASL-25 AI100	100A	

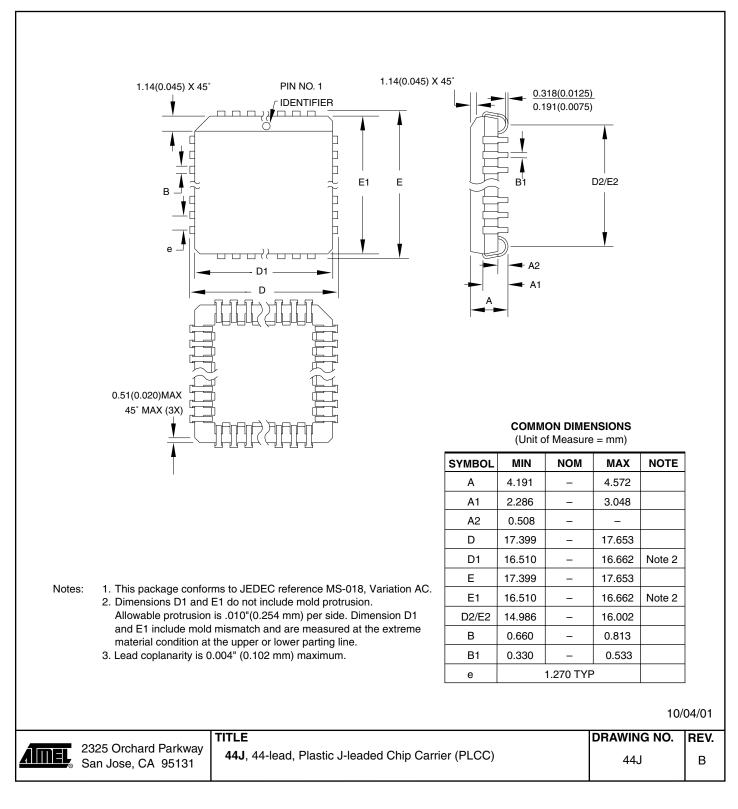
ATF1504ASL Ordering Information

Using "C" Product for Industrial

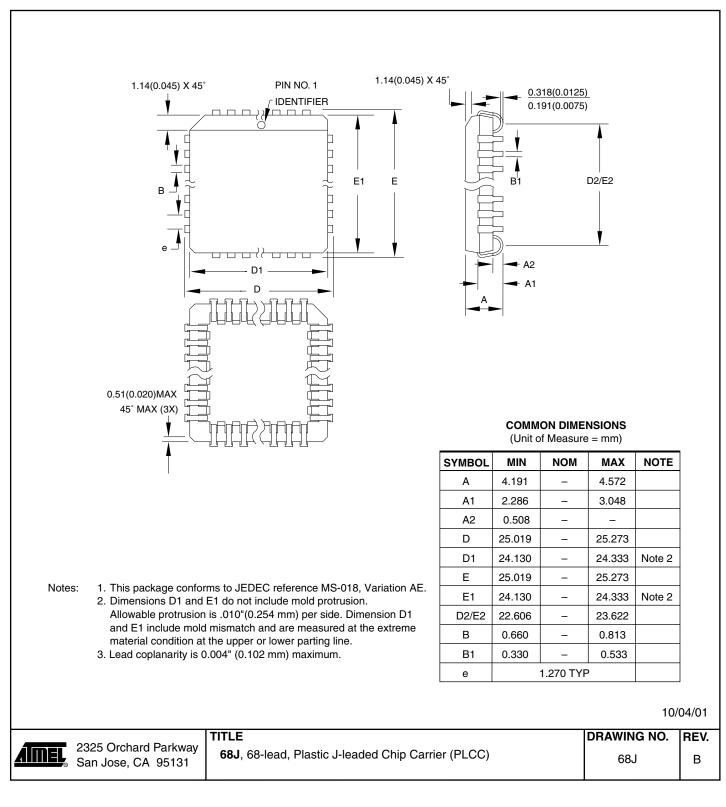
To use commercial product for Industrial temperature ranges, down-grade one speed grade from the "I" to the "C" device (7 ns "C" = 10 ns "I") and de-rate power by 30%.



44J – PLCC



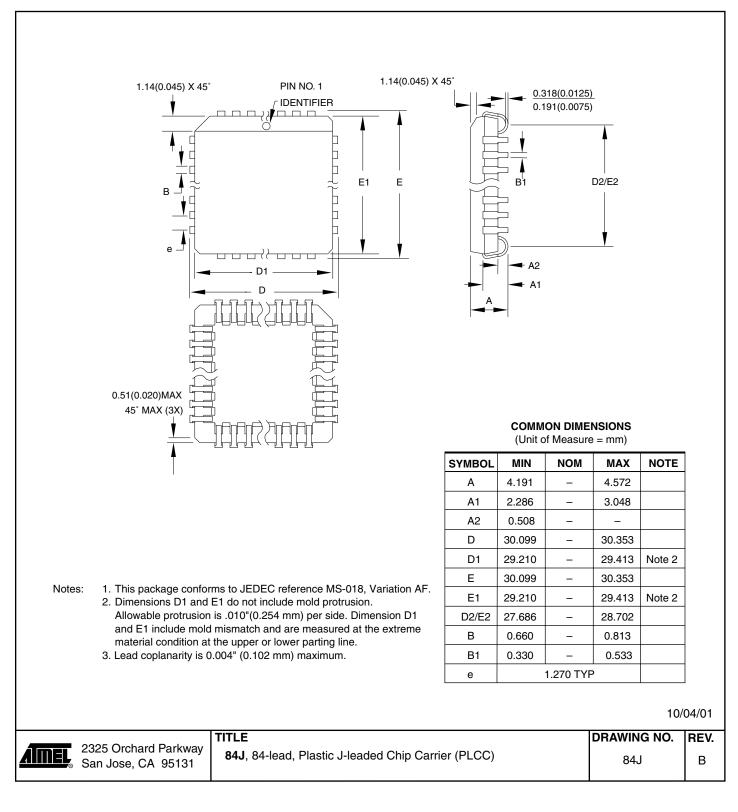
68J – PLCC



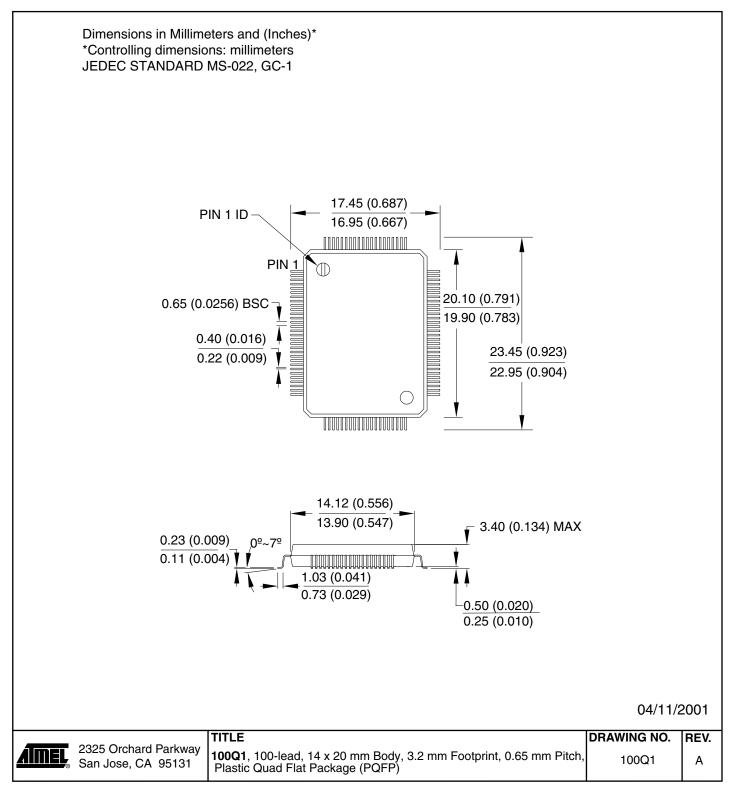




84J – PLCC



100Q1 - PQFP







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